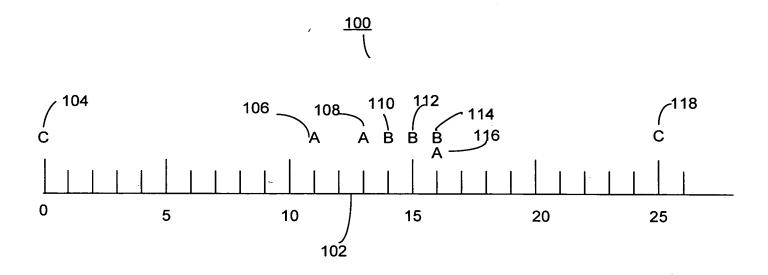
TITLE: SYSTEM/METHOD FOR ANALYZING A PATTERN IN A TIME-STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707 MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229

1/10

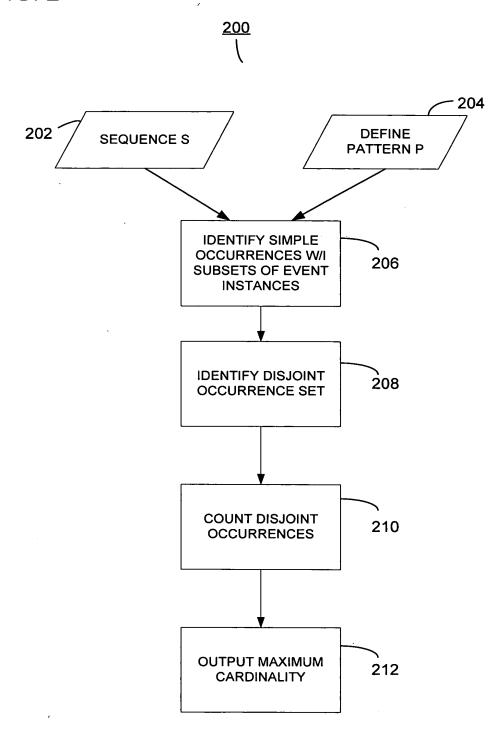
FIG. 1



## STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 2/10

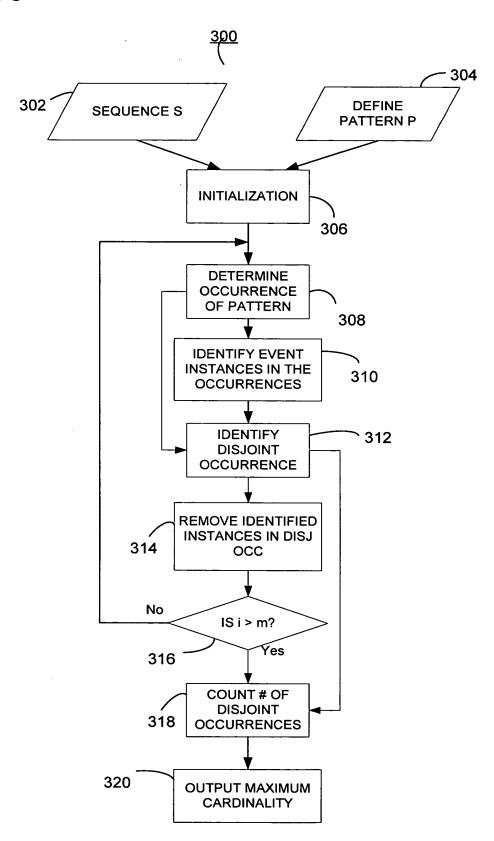
FIG. 2



## STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

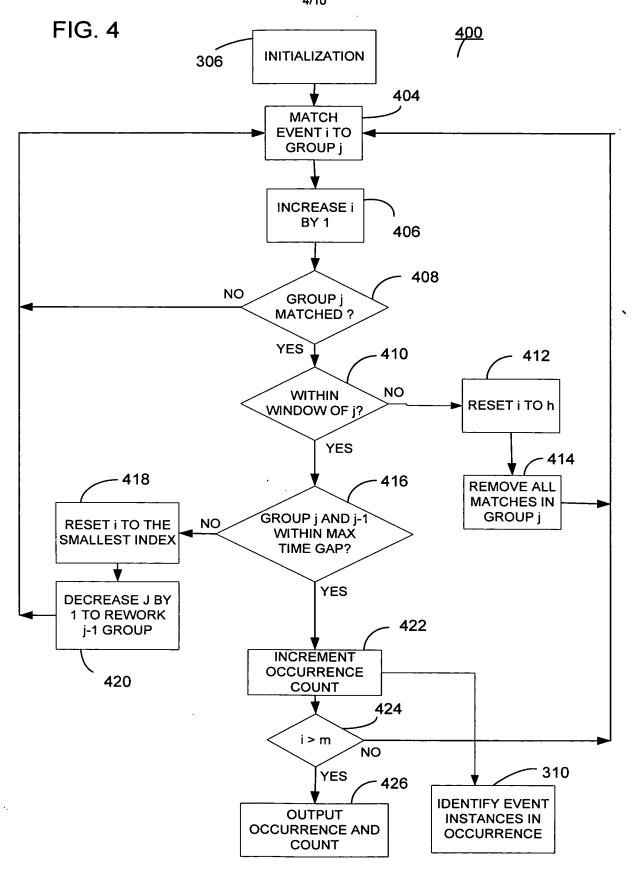
MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 3/10

FIG. 3



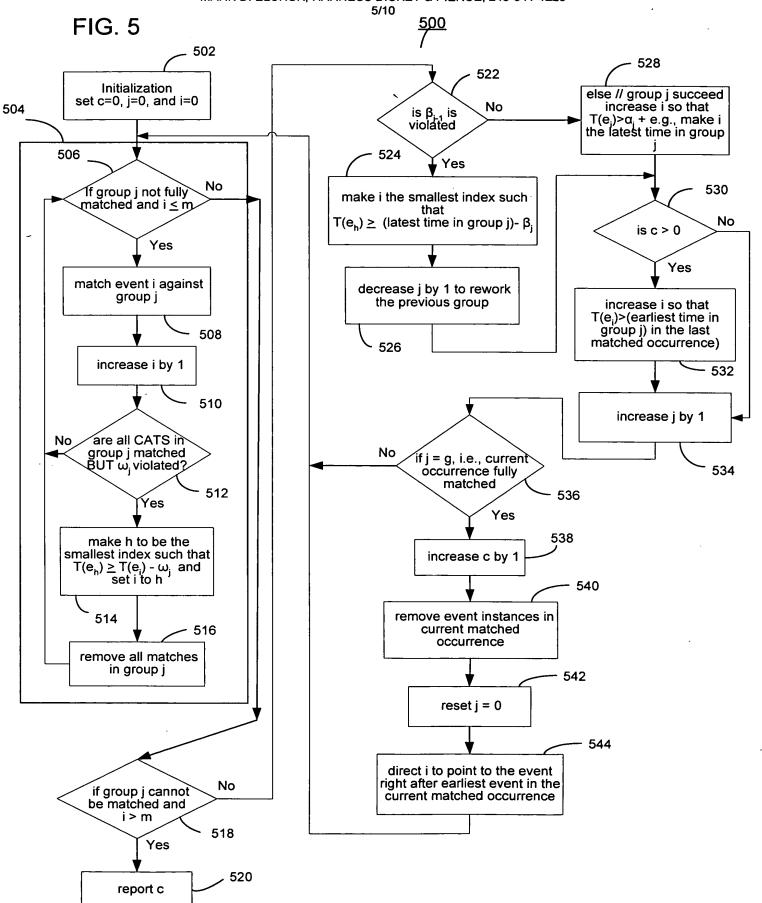
## STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 4/10



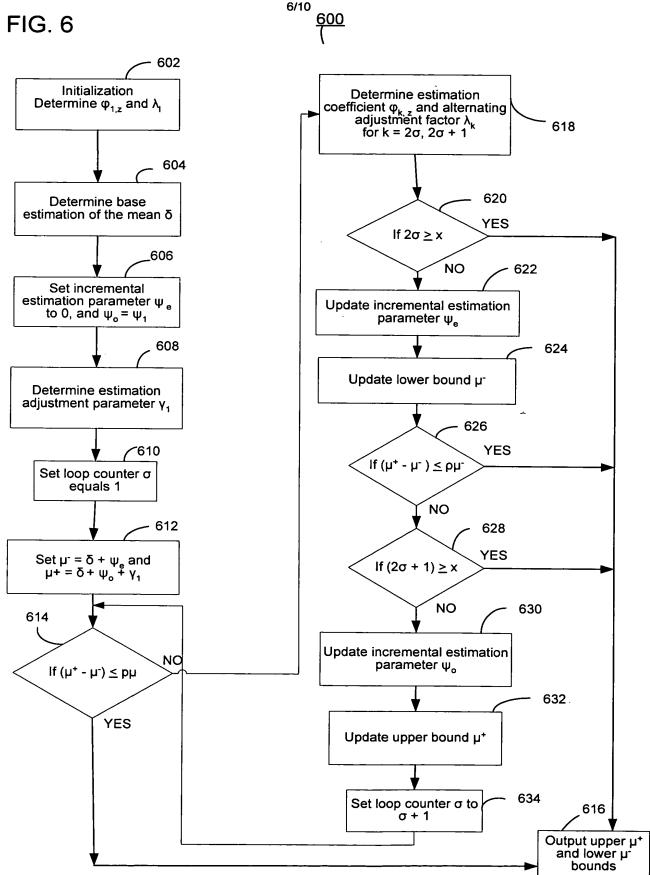
### STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229



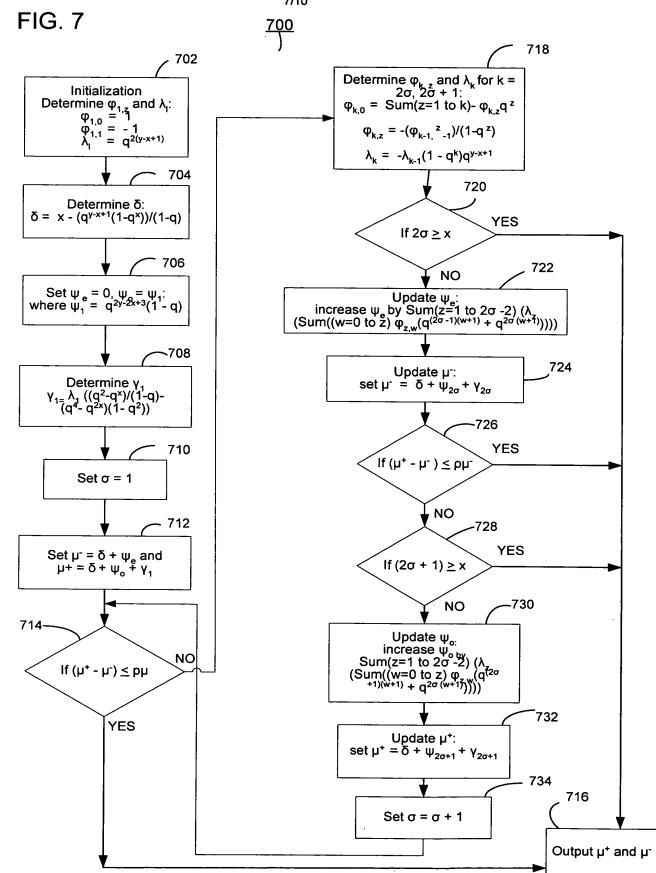
## STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229



# STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG

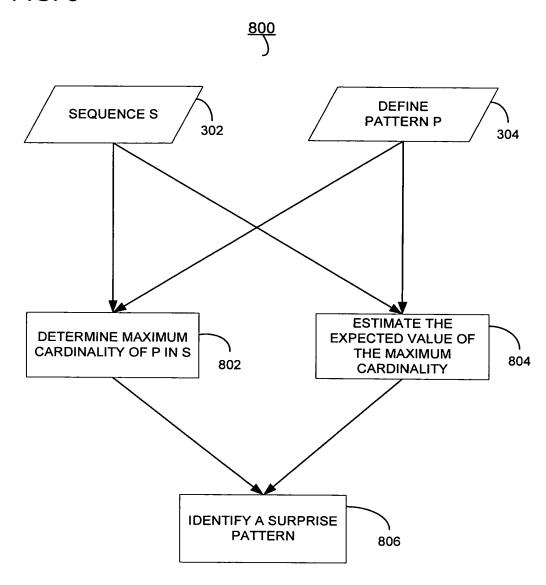
ATTY REF.: 7784-000707 MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229



## TITLE: SYSTEM/METHOD FOR ANALYZING A PATTERN IN A TIME-STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 8/10

FIG. 8

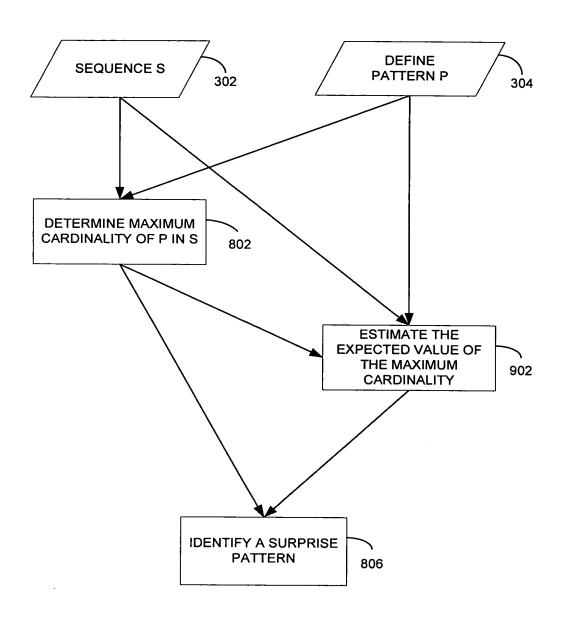


## STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 9/10

FIG. 9





# TITLE: SYSTEM/METHOD FOR ANALYZING A PATTERN IN A TIME-STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG

ATTY REF.: 7784-000707 MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229 10/10

